



# CERTIFICATE OF ACCREDITATION

## ANSI-ASQ National Accreditation Board

500 Montgomery Street, Suite 625, Alexandria, VA 22314, 877-344-3044

This is to certify that  
**SMT Corporation**  
**14 High Bridge Road**  
**Sandy Hook, CT 06482**

has been assessed by ANAB  
and meets the requirements of international standard

## ISO/IEC 17025:2005

while demonstrating technical competence in the fields of

## TESTING

Refer to the accompanying Scope of Accreditation for information regarding the types of calibrations and/or tests to which this accreditation applies.

AT-1733

Certificate Number



ANAB Approval

Certificate Valid: 03/06/2018-10/22/2018  
Version No. 003 Issued: 10/22/2018



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2005

SMT Corporation

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TESTING

Valid to: October 22, 2018

Certificate Number: AT-1733

Non-Destructive Testing

Table with 4 columns: Specific Tests and/or Properties Measured, Specification, Standard, Method, or Test Technique, Items, Materials or Product Tested, Key Equipment or Technology. Rows include Radiographic Examination, Scanning Electron Microscopy (SEM), and Visual Inspection.

Mechanical

Table with 4 columns: Specific Tests and/or Properties Measured, Specification, Standard, Method, or Test Technique, Items, Materials or Product Tested, Key Equipment or Technology. Rows include Resistance to Solvents (RTS) / Scrape Test and Packaging Configuration and Dimensions.

**Mechanical**

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Dynasolve	Internal Procedure: W750-09 IDEA-STD-1010B AS6081	Electrical, Electronic and Electromechanical (EEE) Components	Removal of Residue
Decapsulation and Die Verification	Internal Procedure: W750-21 IDEA-STD-1010B AS6081	Electrical, Electronic and Electromechanical (EEE) Components	Nisene Jet-Etch Acid Decapsulator

**Electrical**

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Capacitance Measurement	MIL-STD-202G METHOD 305A Internal Procedure: W750-03	Electrical, Electronic and Electromechanical (EEE) Components	LCR Meter – Quadtech 7600B
Contact Resistance	MIL-STD-202 Method 307 Internal Procedure: W750-02	Electrical, Electronic and Electromechanical (EEE) Components	Multimeter
Forward voltage drop	MIL-STD-750 METHOD 4011 Internal procedure: W750- 4011.4	Diodes	PXI-4130 Source-Measure Unit PXI-4072 DMM, PXI-5122 Digitizer (Oscilloscope) PXIe-6556 Digital Waveform Generator
Reverse Current Leakage	MIL-STD-750 METHOD 4016 Internal procedure: W750- 4016.4	Diodes	PXI-4130 Source-Measure Unit
Regulator (breakdown) Voltage	MIL-STD-750 METHOD 4022 Internal procedure: W750- 4022	Zener Diodes	PXI-4130 Source-Measure Unit PXI-4072 DMM
Propagation Delay	MIL-STD-883 METHOD 3003 Internal procedure: W883-3003	Microcircuits	PXI-4110 Power Supply PXI-6556 Digital Waveform Generator LeCroy WavePro 7300A 3GHz Oscilloscope

**Electrical**

<b>Specific Tests and/or Properties Measured</b>	<b>Specification, Standard, Method, or Test Technique</b>	<b>Items, Materials or Product Tested</b>	<b>Key Equipment or Technology</b>
Power Supply Current	MIL-STD-883 METHOD 3005 Internal procedure: W883-3005	Microcircuits	PXI-4130 Source-Measure Unit PXI-4110 Power Supply PXI-4072 DMM
High Level Output Voltage	MIL-STD-883 METHOD 3006 Internal procedure: W883-3006	Microcircuits	PXI-4130 Source-Measure Unit PXI-4110 Power Supply PXI-4072 DMM
Low Level Output Voltage	MIL-STD-883 METHOD 3007 Internal procedure: W883-3007	Microcircuits	PXI-4130 Source-Measure Unit PXI-4110 Power Supply PXI-4072 DMM
Low Level Input Current	MIL-STD-883 METHOD 3009 Internal procedure: W883-3009	Microcircuits	PXI-4130 Source-Measure Unit PXI-4110 Power Supply PXI-4072 DMM
High Level Input current	MIL-STD-883 METHOD 3010 Internal procedure: W883-3010	Microcircuits	PXI-4130 Source-Measure Unit PXI-4110 Power Supply PXI-4072 DMM
Output Short Circuit Current	MIL-STD-883 METHOD 3011 Internal procedure: W883-3011	Microcircuits	PXI-4130 Source-Measure Unit PXI-4110 Power Supply PXI-4072 DMM
Functional Testing	MIL-STD-883 METHOD 3014 Internal procedure: W883-3014	Microcircuits	PXI-4110 Power Supply PXI-6556 Digital Waveform Generator
Input Clamp Voltage	MIL-STD-883 METHOD 3022 Internal procedure: W883-3022	Microcircuits	PXI-4130 Source-Measure Unit PXI-4110 Power Supply PXI-4072 DMM

Note:

1. This scope is formatted as part of a single document including Certificate of Accreditation No. AT-1733.



Vice President